



# DB3 Bidirectional Trigger Diode

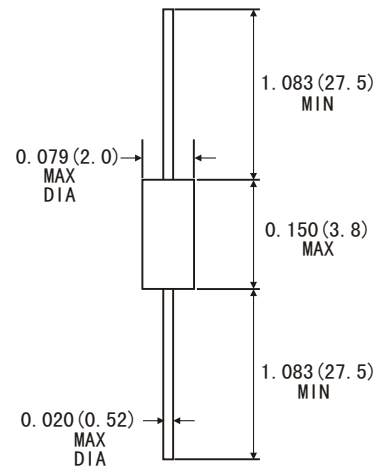
## Features

- Bilateral triggering device
- Glass passivated chip junctions
- low breakover current
- Long-term reliability
- Parameter stability
- High temperature soldering  
260°C/10 seconds at terminals
- Component in accordance to  
RoHS 2002/95/1 and WEEE 2002/96/EC

## Mechanical Date

- **Case:** Glass,hermetically sealed
- **Terminals:** Plated axial leads solderable per  
MIL-STD 202E, method 208C
- **Mounting position:** Any

DO-35(GLASS)



Dimensions in inches and (millimeters)

## Absolute Maximum Ratings

	Symbol	DB3	UNIT
Power dissipation	$P_C$	150	mW
Repetitive peak on-state current @ $t_p=20\mu S$ 、 $F=100Hz$	$I_{TRM}$	2.0	A
Operating junction temperature at $t_p<1s, T_A=25^\circ C$	$T_J$	-40 ~ 125	$^\circ C$
Storage temperature	$T_{STG}$	-40 ~ 125	$^\circ C$

## Electrical Characteristics

( $T_A = 25^\circ C$  unless otherwise noted)

	Symbol	DB3	UNIT
Breakover voltage(See Fig.1)	$V_{BO}$	28	V
		32	V
		36	V
Breakover voltage Symmetry(See Fig.1)	$\Delta V_{BO}$	3.0	V
Minimum dynamic breakover voltage@ $I_{BO}$ to $I_F=10mA$ (See Fig.1)	$\Delta V$	5.0	V
Minimum output voltage(See Fig.2)	$V_O$	5.0	V
Maximum breakover current(See Fig.1)	$I_{BO}$	100	$\mu A$
Rise time(See Fig.3)	$t_r$	1.5	$\mu S$
Maximum leakage current @ $V_B=0.5V_{BO}$ (See Fig.1)	$I_B$	10	$\mu A$



Fig.1 Voltage-Current Characteristic Curve

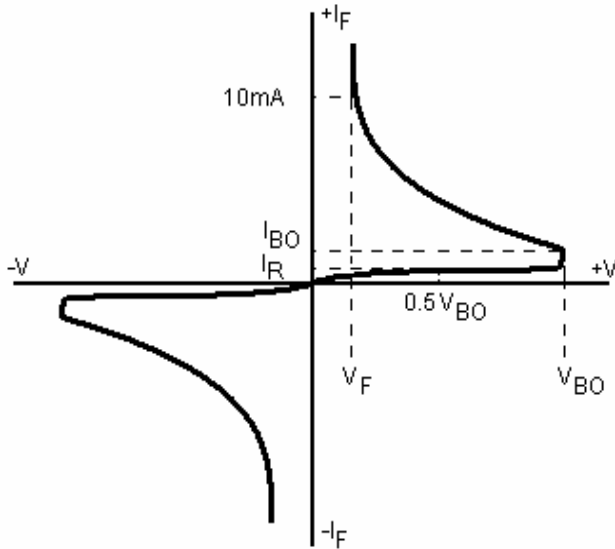


Fig.2 Test Circuit for Output Voltage

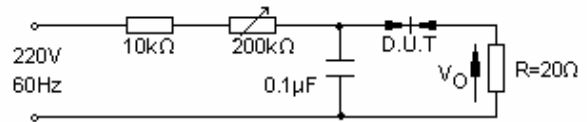


Fig.3 Test Circuit see Fig.2 Adjust R for  $I_p=0.5A$

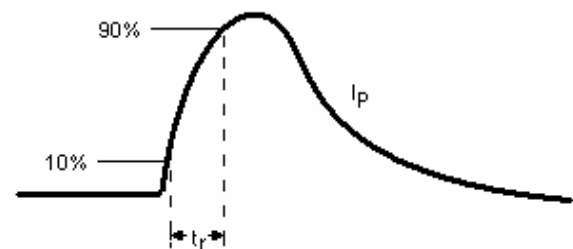


Fig.4 Power Dissipation versus Ambient Temperature (Maximum Values)

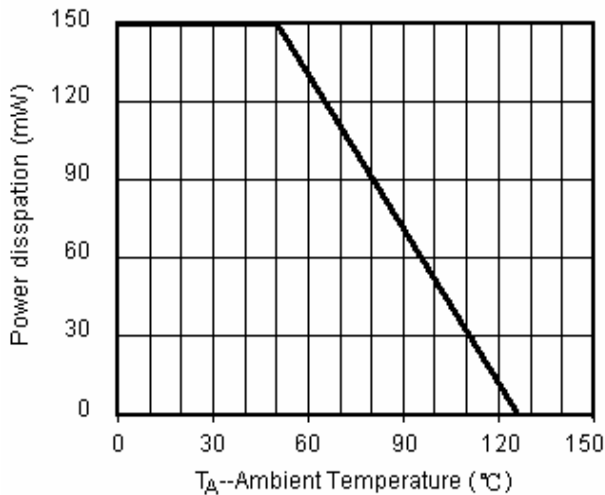


Fig.5 Repetitive Peak Pulse Current versus Pulse Duration(Maximum Values)

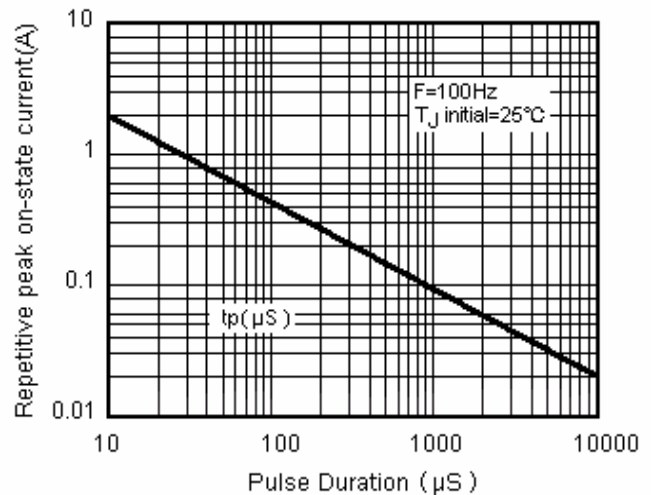


Fig.6 Relative Variation of  $V_{BO}$  versus Junction Temperature (Typical Values)

